

AMENDMENTS TO THE CLAIMS

Please cancel claim 4 and amend claims 1 and 5 to 14 as follows (a complete claim listing is provided below pursuant to 37 CFR 1.121):

1. (Currently Amended) A solid-state image pickup device comprising:
 - a pixel unit including a plurality of unit pixels that perform photoelectric conversion;
 - a driving circuit for driving said pixel unit to control output of a pixel output signal, said driving circuit having a function of performing a normal reading operation for selecting pixels at a normal speed and a high-speed reading operation for selecting pixels at a higher speed than that under said normal reading operation;
 - an output signal processing circuit for subjecting the pixel output signal outputted from said pixel unit during said normal reading operation performed by according to the driving of said driving circuit to predetermined signal processing, and outputting a resulting pixel output signal;
 - a pixel defect determining circuit for capturing the pixel output signal outputted from said pixel unit during said high-speed reading operation performed by according to the driving of said driving circuit, and determining a pixel defect by comparing the pixel output signal with a predetermined reference signal; and
 - a timing generator for supplying a predetermined operating pulse to said driving circuit, said output signal processing circuit, and said pixel defect determining circuit.

2. (Original) The solid-state image pickup device as claimed in claim 1, further comprising a selecting circuit for selectively operating said output signal processing circuit in a normal output mode and said pixel defect determining circuit in a defect test mode.

3. (Original) The solid-state image pickup device as claimed in claim 1, wherein said driving circuit has a function of reading out the unit pixels of said pixel unit by one pixel or a pixel column or a pixel row.

Claim 4. (Cancelled).

5. (Currently Amended) The solid-state image pickup device as claimed in claim 1 4, wherein said driving circuit selects a pixel to read out a signal under said high-speed reading operation in a time of testing said pixel unit for a defect.

6. (Currently Amended) The solid-state image pickup device as claimed in claim 1, wherein ~~said driving circuit has a function of performing~~ a normal reading operation comprises for selecting pixels to read out a signal by one pixel or a pixel column or a pixel row, and said high-speed reading operation comprises a multi-pixel reading operation for selecting more pixels to read out a signal than that under said normal reading operation.

7. (Currently Amended) The solid-state image pickup device as claimed in claim 6,

wherein said driving circuit selects pixels to read out a signal under said high-speed
~~multi-pixel~~ reading operation in a time of testing said pixel unit for a defect.

8. (Currently Amended) The solid-state image pickup device as claimed in claim 1,
wherein said ~~driving circuit has a function of performing~~ a normal reading operation
comprises for selecting pixels to read out a signal by one pixel or a pixel column or a pixel row,
and said a multi-pixel high-speed reading operation comprises for selecting more pixels to read
out a signal than that under said normal reading operation at a higher speed than that under said
normal reading operation.

9. (Currently Amended) The solid-state image pickup device as claimed in claim 8,
wherein said driving circuit selects pixels to read out a signal under said ~~multi-pixel~~
high-speed reading operation in a time of testing said pixel unit for a defect.

10. (Currently Amended) A pixel defect testing method for a solid-state image pickup
device, said solid-state image pickup device comprising: a pixel unit including a plurality of unit
pixels that perform photoelectric conversion; a driving circuit for driving said pixel unit to
control output of a pixel output signal; an output signal processing circuit for subjecting the pixel
output signal outputted from said pixel unit according to the driving of said driving circuit to
predetermined signal processing, and outputting a resulting pixel output signal; and a timing

generator for supplying a predetermined operating pulse to said driving circuit and said output signal processing circuit;

wherein said driving circuit functions to perform a normal reading operation for selecting pixels at a normal speed and a high-speed operation for selecting pixels at a higher speed than under said normal reading operation; and

wherein the pixel output signal outputted from said pixel unit during said high-speed operation performed by according to the driving of said driving circuit is captured independently of said output signal processing circuit, and a pixel defect is determined by comparing the captured pixel output signal with a predetermined reference signal, and a defect test on the captured pixel output signal outputted from said pixel unit is performed on the basis of an operating pulse from said timing generator.

11. (Currently Amended) The pixel defect testing method of a solid-state image pickup device as claimed in claim 10,

wherein said driving circuit selects a pixel at a higher speed during said high-speed operation than at a time of normal output to read out a signal in a time of testing said pixel unit for a defect.

12. (Currently Amended) The pixel defect testing method of a solid-state image pickup device as claimed in claim 10,

wherein said driving circuit selects more pixels during said high-speed operation than at a time of normal output to read out a signal in a time of testing said pixel unit for a defect.

13. (Currently Amended) The pixel defect testing method of a solid-state image pickup device as claimed in claim 10,

wherein said driving circuit selects more pixels at a higher speed during said high-speed operation than at a time of normal output to read out a signal in a time of testing said pixel unit for a defect.

14. (Currently Amended) The pixel defect testing method of a solid-state image pickup device as claimed in claim 10,

wherein in parallel with a defect test on said pixel unit, a predetermined test signal is inputted to other circuits mounted on the same an identical chip and a defect test on said other circuits is performed.